

Amendments to the Claims:

Claim 1 (Canceled)

2. (Currently amended) The ~~infrared image generation device~~ system of claim [[1]]
18, wherein said ~~laser light~~ source element is a diode pumped solid-state laser light source.

Claim 3 (Canceled)

4. (Currently amended) The ~~infrared image generation device~~ system of claim [[1]]
18, wherein said at least one ~~scanner~~ scanning element comprises an amplifier.

5. (Currently amended) The ~~infrared image generation device~~ system of claim [[1]]
18, wherein said target ~~plate~~ element comprises:

a transparent heat sink layer facing said at least one ~~scanner~~ scanning element;
an insulator layer adjacent the transparent heat sink layer; and
an emissive layer that is at least opaque adjacent the insulator layer.

6. (Currently amended) The ~~infrared image generation device~~ system of claim 5,
wherein the transparent heat sink layer is made of diamond.

7. (Currently amended) The ~~infrared image generation device~~ system of claim 5,
wherein the insulator layer is made of heat-resistant glass.

8. (Currently amended) The ~~infrared image generation device~~ system of claim 5,
wherein the emissive layer comprises carbon.

9. (Currently amended) The ~~infrared image generation device system~~ of claim [[1]] 18, further comprising a collimator disposed opposite said at least one ~~scanner~~ scanning element relative to said target ~~plate~~ target element.

Claim 10. (Canceled)

11. (Currently amended) A method for generating an infrared image, comprising:
providing laser light;
scanning laser light across a first side of a target plate; and
displaying at least one infrared image on a second side of the target plate, opposite the first side, in response to the laser light scanned thereacross, wherein displaying the at least one infrared image comprising displaying at least one infrared thermal image having hotter and cooler portions at different respective temperatures; and
determining whether a sensor which faces the second side of the target plate detects the at least one infrared image.

12. (Original) The method for generating an infrared image of claim 11, wherein generating at least one infrared image comprises generating at least one infrared image having at least one portion that is a temperature of at least 1000 Kelvin.

13. (Currently amended) The method for generating an infrared image of claim 11, further comprising collimating the at least one generated image for viewing by [[a]] the sensor.

14. (Original) The method for generating an infrared image of claim 11, further comprising drawing heat out of the target plate after scanning the laser light across the target plate to prevent the laser light from heating portions of the target plate other than the portion on which the laser light is incident.

15. (Original) The method for generating an infrared image of claim 11, wherein providing the laser light comprises controlling a laser light source to transmit the laser light at at least one power level.

16. (Original) The method for generating an infrared image of claim 11, wherein generating the at least one image comprises receiving the laser light having a first power level to generate at least one portion of the image having a first temperature and receiving the laser light having a second power level to generate at least one portion of the image having a second temperature, wherein the second power level and second temperature are less than the first power level and first temperature, respectively.

17. (Original) The method for generating an infrared image of claim 11, wherein generating the at least one image comprises receiving the laser light for a first period of time to generate at least one portion of the image having a first temperature and receiving the laser light for a second period of time to generate at least one portion of the image having a second temperature, wherein the second period of time and second temperature are less than the first period of time and first temperature, respectively.

18. (Previously presented) A system for testing an infrared sensor, comprising:
a source element configured to provide laser light;
at least one scanning element configured to receive the laser light from said source element and further configured to redirect the laser light;
a processing element configured to control operation of said at least one scanning element to generate at least one infrared image;
a target element configured to receive the redirected laser light from said at least one scanning element on a first side of said target element and further configured to display at least one infrared image on a second side of said target element that is opposite the first side; and

an infrared sensor element facing the second side of said target element, wherein said processing element is also configured to determine whether said sensor element detects the at least one infrared image.

19. (Previously presented) The system for testing an infrared sensor of claim 18, wherein said processing element is configured to control output power of said source element.

20. (Previously presented) The system for testing an infrared sensor of claim 18, further comprising a relay optical element configured to focus the at least one infrared image at a focal point of said infrared sensor element.

21. (Previously presented) The system for testing an infrared sensor of claim 18, wherein said target element is configured to display an image having at least one portion that is a temperature of at least 1000 Kelvin.

22. (Previously presented) The system for testing an infrared sensor of claim 18, wherein said target element comprises a heat sink element configured to draw heat out of said target element to prevent the laser light from heating portions of said target element other than the portion on which the laser light is incident.